

RF Test Report

For

Applicant Name:

Address:

EUT Name:

Brand Name:

Model Number:

Shenzhen Semetor Electronics Co., LTD

B3, 3th floor, guanglong building, No.162, pingxin north road, hehua community, pinghu street, longgang district, shenzhen city, guangdong

F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen,

MUTI-FUNCTION WIRELESS CHARGER



COLSUR[®]

S05

China

Pass

Issued By

BTF Testing Lab (Shenzhen) Co., Ltd.

Company Name:

Address:

Report Number: Test Standards: FCC ID: Test Conclusion: Test Date: Date of Issue:

Prepared By:

Approved By:

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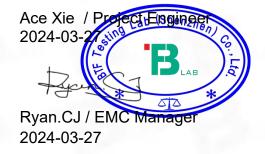
BTF240313R00304

2AYRH-S05

2024-03-27

47 CFR Part 15 Subpart C

2024-03-14 to 2024-03-27



Date:

Date:

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Revision History					
Version Issue Date Revisions Content					
R_V0	2024-03-27	Original			
Note:	Once the revision has	Once the revision has been made, then previous versions reports are invalid.			

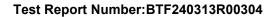




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1. Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.	
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China	
Phone Number:	+86-0755-23146130	
Fax Number:	+86-0755-23146130	

1.2 Identification of the Responsible Testing Location

Test Location:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Description:	All measurement facilities used to collect the measurement data are located at F101,201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
FCC Registration Number:	518915
Designation Number:	CN1330

1.3 Laboratory Condition

Ambient Temperature:	20°C to 25°C
Ambient Relative Humidity:	45% to 55%
Ambient Pressure:	100 kPa to 102 kPa

1.4 Announcement

- (1) The test report reference to the report template version v0.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
- (6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.



2. Product Information

2.1 Application Information

Company Name:	Shenzhen Semetor Electronics Co., LTD	
Andress.	B3, 3th floor, guanglong building, No.162, pingxin north road, hehua community, pinghu street, longgang district, shenzhen city, guangdong	

2.2 Manufacturer Information

Company Name:	Shenzhen Semetor Electronics Co., LTD		
Address:	B3, 3th floor, guanglong building, No.162, pingxin north road, hehua community, pinghu street, longgang district, shenzhen city, guangdong		

2.3 Factory Information

Company Name:	Shenzhen Semetor Electronics Co., LTD
Address:	B3, 3th floor, guanglong building, No.162, pingxin north road, hehua community, pinghu street, longgang district, shenzhen city, guangdong

2.4 General Description of Equipment under Test (EUT)

EUT Name:	MUTI-FUNCTION WIRELESS CHARGER
Under Test Model Name	S05

2.5 Technical Information

	Network and Wireless connectivity	Wireless power transmission
The requirement for the following technical information of the EUT was tested in this report:		
	Modulation Type	ASK
	Antenna type	Coil Antenna
	Frequency Range	The operation frequency is 121KHz to 146KHz.



3. Summary of Test Results

3.1 Test Standards

No. Identity		Document Title
1	47 CFR Part 15, Subpart C	Intentional Radiators
2	ANSI C63.10-2013	American National Standard for Testing Unlicensed Wireless Devices

3.2 Summary of Test Result

No.	Description	FCC Part No.	Test Result	Test By	Verdict	Remark
1	Antenna Requirements	15.203		Aria Zhang	Pass	
2	20dB Occupied Bandwidth	2.1049	ANNEX A.1	Aria Zhang	Pass	
3	AC Power Line Conducted Emissions	15.207	ANNEX A.2	Aria Zhang	Pass	
4	Spurious Emissions	15.209	ANNEX A.3	Aria Zhang	Pass	

3.3 Uncertainty of Test

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2 and TR100 028-1/-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
	value
Occupied Channel Bandwidth	69 KHz
RF output power, conducted	0.87 dB
Power Spectral Density, conducted	0.69 dB
Unwanted Emissions, conducted	0.94 dB
All emissions, radiated(<1GHz)	4.12 dB
All emissions, radiated(>1GHz)	4.16 dB
Temperature	0.82 °C
Humidity	4.1 %



4. Test Configuration

4.1 Environment Condition

Environment		Selected Va	alues During Tests	
Parameter	Temperature	Voltage	Relative Humidity	Ambient Pressure
Normal Temperature, Normal Voltage (NTNV)	-40°C to 85°C	DC 9V	30% to 60%	100 kPa to 102 kPa

4.2 Test Equipment List

	Conc	lucted Method	d Test			
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
MXA Signal Analyzer	KEYSIGHT	N9020A	MY50410020	2023.11.16	2024.11.15	\boxtimes
WIDEBAND RADIO COMMNUNICATION TESTER	Rohde & Schwarz	CMW500	161997	2023.11.16	2024.11.15	\boxtimes
Adjustable Direct Current Regulated Power Supply	Dongguan Tongmen Electronic Technology Co., LTD	etm-6050c	20211026123	1	/	
Programmable constant temperature and humidity box	ZZCKONG	ZZ-K02A	20210928007	2023.11.16	2024.11.15	
RF Sensor Unit	Techy	TR1029-2	/	/	/	\boxtimes
RF Control Unit	Techy	TR1029-1	/	/	/	\boxtimes
RFTest software	/	V1.00	/	/	/	\boxtimes

	Radiated Method Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use	
SIGNAL ANALYZER	ROHDE&SCHWARZ	FSQ40	100010	2023.11.16	2024.11.15	\boxtimes	
EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI7	101032	2023.11.16	2024.11.15	\boxtimes	
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2023.11.13	2024.11.12	\boxtimes	
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2023.11.13	2024.11.12	\boxtimes	
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/	\boxtimes	
RE Cable	REBES Talent	UF2-NMNM- 10m	21101570	/	1	\boxtimes	

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RE Cable	REBES Talent	UF1-SMASMAM- 10m	21101566	1	/	\boxtimes
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	/	/	\boxtimes
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	/	/	\boxtimes
RE Cable	REBES Talent	UF1-SMASMAM-1m	21101568	/	/	\boxtimes
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	/	/	\boxtimes
RE Cable	REBES Talent	UF1-SMASMAM- 10m	21101566	/	/	\boxtimes
Preamplifier	SCHWARZBECK	BBV9744	00246	/	/	\boxtimes
Horn Antenna	Schwarzbeck	BBHA9120D	2597	2022.05.22	2024.05.21	\boxtimes
Low Noise Pre- amplifier	Sket	LNPA_1840G-50	SK2022032902	2023.3.26	2024.3.25	\boxtimes
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	2023.3.26	2024.3.25	\boxtimes
Broadband Preamplilifier	Schwarzbeck	BBV9718D	00008	2023.3.26	2024.3.25	\boxtimes

	Conducted disturbance Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use	
EMI Receiver	ROHDE&SCHWARZ	ESCI3	101422	2023.11.15	2024.11.14	\boxtimes	
LISN	AFJ	LS16/110VAC	16010020076	2023.02.23	2024.02.22		
V-LISN	SCHWARZBECK	NSLK 8127	01073	2023.11.16	2024.11.15	\boxtimes	
Coaxial Switcher	SCHWARZBECK	CX210	CX210	1	1	\boxtimes	
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	/	/	\boxtimes	
EZ_EMC	Frad	EMC-CON 3A1.1+	/	1	/	\square	

4.3 Test Auxiliary Equipment

Description	Manufacturer	Model	Serial No.	Length	Description	Use
Adapter	Huawei	HW- 059200CHQ	1	1	/	\boxtimes
Wireless load	YBZ	/	1	1	15.0W MAX	\boxtimes

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4.4 Test Mode

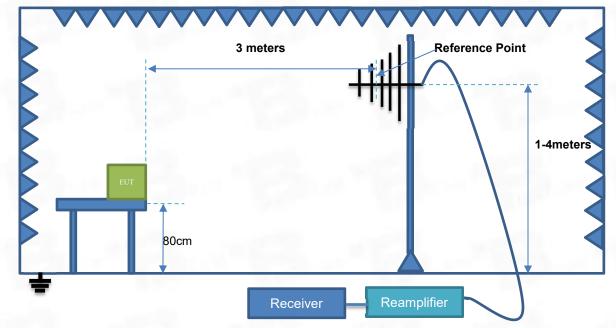
Test item	Test mode	Description
Radiated&Conducted Test cases	ANT1	Mode 1: AC/DC Adapter + EUT + Wireless load (Full Load) Mode 2: AC/DC Adapter + EUT + Wireless load (Half Load) Mode 3: AC/DC Adapter + EUT + Wireless load (Null Load) Mode 4: EUT + Wireless load (Full Load) Mode 5: EUT + Wireless load (Half Load) Mode 6: EUT + Wireless load (Null Load)
	No Loads	AC/DC Adapter + EUT(Null Load)

Note: All the mode have been tested, and only the worst case of mode are in the report.

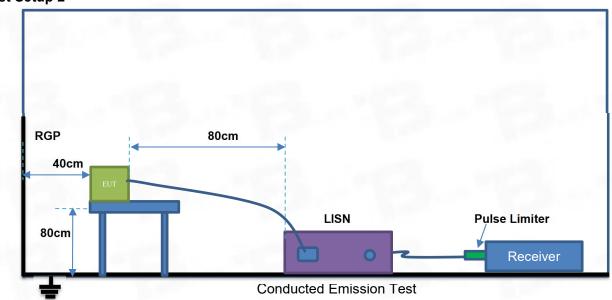


4.5 Test Setup

Test Setup 1



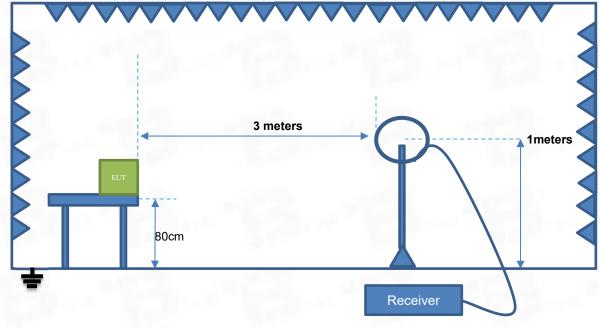
Radiation Test (30MHz – 1GHz)



Test Setup 2

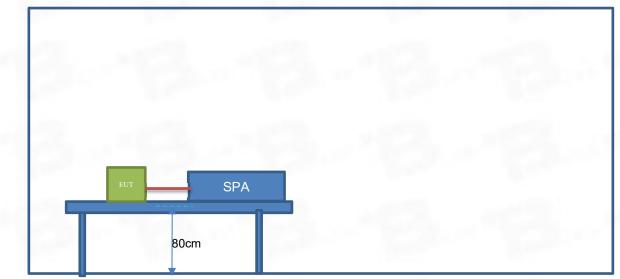


Test Setup 3



Radiation Test (9k - 30MHz)

Test Setup 4





5. Test Items 5.1 Antenna Requirements

FCC §15.203; RSS-247, 5.4(f)

An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section. The manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited. This requirement does not apply to carrier current devices or to devices operated under the provisions of § 15.211, § 15.213, § 15.217, § 15.219, or § 15.221. Further, this requirement does not apply to intentional radiators that must be professionally installed, such as perimeter protection systems and some field disturbance sensors, or to other intentional radiators which, in accordance with

§ 15.31(d), must be measured at the installation site. However, the installer shall be responsible for ensuring that the proper antenna is employed so that the limits in this part are not exceeded.

If directional gain of transmitting antennas is greater than 6 dBi, the power shall be reduced by the same level in dB comparing to gain minus 6 dBi. For the fixed point-to-point operation, the power shall be reduced by one dB for every 3 dB that the directional gain of the antenna exceeds 6 dBi. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the FCC rule.

The EUT uses an Integral Antenna which in accordance to Section 15.203 is considered sufficient to comply with the provisions of this section.



5.2 20dB Occupied Bandwidth

5.2.1 Limit

FCC Part 2.1049.

5.2.2 Test Setup

See section 4.4 for test setup 4 description for the antenna port. The photo of test setup please refer to ANNEX B

5.2.3 Test Procedure

- 1. The transmitter output was connected to the spectrum analyzer through an attenuator, the pathloss was compensated to the results for each measurement.
- 2. Set to the maximum power setting and enable the EUT transmit continuously
- Use the following spectrum analyzer settings: Span = approximately 2 to 3 times the 20 dB bandwidth, centered on a hopping channel RBW≥1% of the 20 dB bandwidth, VBW ≥ RBW Sweep = auto, Detector function = peak, Trace = max hold
- 4. Measure and record the results in the test report.

5.2.4 Test Result

Please refer to ANNEX A.1

5.3 AC Power Line Conducted Emissions

5.3.1 Limit

FCC §15.207

For an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150 kHz to 30 MHz shall not exceed the limits in the following table, as measured using a 50μ H/ 50Ω line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBµV)		
(MHz)	Quai-peak	Average	
0.15 - 0.50	66 to 56	56 to 46	
0.50 - 5	56	46	
0.50 - 30	60	50	

5.3.2 Test Setup

See section 4.4 for test setup description for setup 2. The photo of test setup please refer to ANNEX B

5.3.3 Test Procedure

The maximum conducted interference is searched using Peak (PK), if the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. Refer to recorded points and plots below.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

5.3.4 Test Result

Please refer to ANNEX A.2

NOTE:

- 1. Results (dBuV) = Reading (dBuV) + Factor (dB)
 - The reading level is calculated by software which is not shown in the sheet
- 2. Factor = Insertion loss + Cable loss
- 3. Over limit = Results Limit.



5.4 Radiated Spurious Emission

5.4.1 Limit

FCC §15.209&15.247(d); RSS-247, 5.5

Radiated emission outside the frequency band attenuation below the general limits specified in FCC section 15.209(a) is not required. In addition, radiated emissions which fall in the restricted bands, as defined in FCC section 15.205(a), must also comply with the radiated emission limits specified in FCC section 15.209(a). According to FCC section 15.209 (a), except as provided elsewhere in this subpart, the emissions from an intentional radiator shall not exceed the field strength levels specified in the following table:

Frequency (MHz)	Field Strength (µV/m)	Measurement Distance (m)
0.009 - 0.490	2400/F(kHz)	300
0.490 - 1.705	24000/F(kHz)	30
1.705 - 30.0	30	30
30 - 88	100	3
88 - 216	150	3
216 - 960	200	3
Above 960	500	3

Note:

1. Field Strength (dB μ V/m) = 20*log[Field Strength (μ V/m)].

2. In the emission tables above, the tighter limit applies at the band edges.

3. For Above 1000 MHz, the emission limit in this paragraph is based on measurement instrumentation employing an average detector, measurement using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit.

4. For above 1000 MHz, limit field strength of harmonics: 54dBuV/m@3m (AV) and 74dBuV/m@3m (PK).

5.4.2 Test Setup

See section 4.4 for test setup description for setup 1 and 3. The photo of test setup please refer to ANNEX B

5.4.3 Test Procedure

Since the emission limits are specified in terms of radiated field strength levels, measurements performed to demonstrate compliance have traditionally relied on a radiated test configuration. Radiated measurements remain the principal method for demonstrating compliance to the specified limits; however antenna-port conducted measurements are also now acceptable to demonstrate compliance (see below for details). When radiated measurements are utilized, test site requirements and procedures for maximizing and measuring radiated emissions that are described in ANSI C63.10 shall be followed.

Antenna-port conducted measurements may also be used as an alternative to radiated measurements for demonstrating compliance in the restricted frequency bands. If conducted measurements are performed, then proper impedance matching must be ensured and an additional radiated test for cabinet/case spurious



emissions is required.

General Procedure for conducted measurements in restricted bands:

a) Measure the conducted output power (in dBm) using the detector specified (see guidance regarding measurement procedures for determining quasi-peak, peak, and average conducted output power, respectively).

b) Add the maximum transmit antenna gain (in dBi) to the measured output power level to determine the EIRP level (see guidance on determining the applicable antenna gain)

c) Add the appropriate maximum ground reflection factor to the EIRP level (6 dB for frequencies \leq 30 MHz, 4.7 dB for frequencies between 30 MHz and 1000 MHz, inclusive and 0 dB for frequencies > 1000 MHz).

d) For devices with multiple antenna-ports, measure the power of each individual chain and sum the EIRP of all chains in linear terms (e.g., Watts, mW).

e) Convert the resultant EIRP level to an equivalent electric field strength using the following relationship:

E = EIRP - 20log D + 104.8

where:

E = electric field strength in $dB\mu V/m$,

EIRP = equivalent isotropic radiated power in dBm D = specified measurement distance in meters.

f) Compare the resultant electric field strength level to the applicable limit.

g) Perform radiated spurious emission test.

Quasi-Peak measurement procedure

The specifications for measurements using the CISPR quasi-peak detector can be found in Publication 16 of the International Special Committee on Radio Frequency Interference (CISPR) of the International Electrotechnical Commission.

As an alternative to CISPR quasi-peak measurement, compliance can be demonstrated to the applicable emission limits using a peak detector.

Peak power measurement procedure:

Peak emission levels are measured by setting the instrument as follows:

a)RBW = as specified in Table 1.

b)VBW \geq 3 x RBW.

c)Detector = Peak.

d)Sweep time = auto.

e)Trace mode = max hold.

f)Allow sweeps to continue until the trace stabilizes. (Note that the required measurement time may be longer



for low duty cycle applications).

Table 1—RBW as a function of frequency

Frequency	RBW
9-150 kHz	200-300 Hz
0.15-30 MHz	9-10 kHz
30-1000 MHz	100-120 kHz
> 1000 MHz	1 MHz

If the peak-detected amplitude can be shown to comply with the average limit, then it is not necessary to perform a separate average measurement.

Trace averaging across on and off times of the EUT transmissions followed by duty cycle correction:

If continuous transmission of the EUT (i.e., duty cycle \geq 98 percent) cannot be achieved and the duty cycle is constant (i.e., duty cycle variations are less than ± 2 percent), then the following procedure shall be used:

a) The EUT shall be configured to operate at the maximum achievable duty cycle.

b) Measure the duty cycle, x, of the transmitter output signal as described in section 6.0.

c) RBW = 1 MHz (unless otherwise specified).

d) VBW \geq 3 x RBW.

e) Detector = RMS, if span/(# of points in sweep) \leq (RBW/2). Satisfying this condition may require increasing the number of points in the sweep or reducing the span. If this condition cannot be satisfied, then the detector mode shall be set to peak.

f) Averaging type = power (i.e., RMS).

1) As an alternative, the detector and averaging type may be set for linear voltage averaging.

2) Some instruments require linear display mode in order to use linear voltage averaging. Log or dB averaging shall not be used.

g) Sweep time = auto.

h) Perform a trace average of at least 100 traces.

i) A correction factor shall be added to the measurement results prior to comparing to the emission limit in order to compute the emission level that would have been measured had the test been performed at 100 percent duty cycle. The correction factor is computed as follows:

1) If power averaging (RMS) mode was used in step f), then the applicable correction factor is $10 \log(1/x)$, where x is the duty cycle.

2) If linear voltage averaging mode was used in step f), then the applicable correction factor is 20 $\log(1/x)$, where x is the duty cycle.

3) If a specific emission is demonstrated to be continuous (\geq 98 percent duty cycle) rather than turning on and off with the transmit cycle, then no duty cycle correction is required for that emission.

NOTE: Reduction of the measured emission amplitude levels to account for operational duty factor is not



permitted. Compliance is based on emission levels occurring during transmission - not on an average across on and off times of the transmitter.

Determining the applicable transmit antenna gain:

A conducted power measurement will determine the maximum output power associated with a restricted band emission; however, in order to determine the associated EIRP level, the gain of the transmitting antenna (in dBi) must be added to the measured output power (in dBm).

Since the out-of-band characteristics of the EUT transmit antenna will often be unknown, the use of a conservative antenna gain value is necessary. Thus, when determining the EIRP based on the measured conducted power, the upper bound on antenna gain for a device with a single RF output shall be selected as the maximum in-band gain of the antenna across all operating bands, or 2 dBi, whichever is greater. However, for devices that operate in multiple frequency bands while using the same transmit antenna, the highest gain of the antenna within the operating band nearest in frequency to the restricted band emission being measured may be used in lieu of the overall highest gain when the emission is at a frequency that is within 20 percent of the nearest band edge frequency, but in no case shall a value less than 2 dBi be used.

See KDB 662911 for guidance on calculating the additional array gain term when determining the effective antenna gain for a EUT with multiple outputs occupying the same or overlapping frequency ranges in the same band.

Radiated spurious emission test:

An additional consideration when performing conducted measurements of restricted band emissions is that unwanted emissions radiating from the EUT cabinet, control circuits, power leads, or intermediate circuit elements will likely go undetected in a conducted measurement configuration. To address this concern, a radiated test shall be performed to ensure that emissions emanating from the EUT cabinet (rather than the antenna port) also comply with the applicable limits.

For these cabinet radiated spurious emission measurements the EUT transmit antenna may be replaced with a termination matching the nominal impedance of the antenna. Procedures for performing radiated measurements are specified in ANSI C63.10. All detected emissions shall comply with the applicable limits.

The measurement frequency range is from 30MHz to the 10th harmonic of the fundamental frequency. The Turn Table is actuated to turn from 0° to 360°, and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

The power of the EUT transmitting frequency should be ignored.

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

Use the following spectrum analyzer settings:



Span = wide enough to fully capture the emission being measured RBW = 1 MHz for f ≥ 1 GHz, 100 kHz for f < 1 GHz VBW ≥ RBW Sweep = auto Detector function = peak Trace = max hold

5.4.4 Test Result

Please refer to ANNEX A.3

NOTE:

1. Results (dBuV) = Reading (dBuV) + Factor (dB)

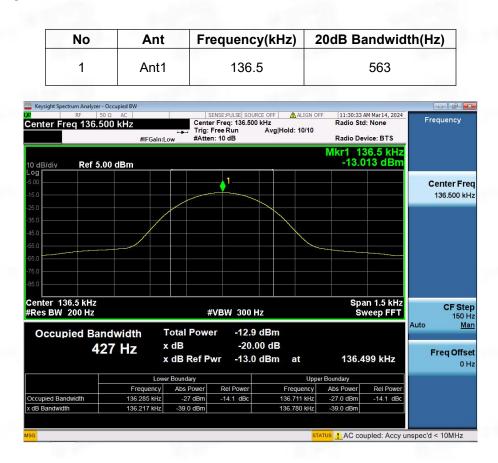
The reading level is calculated by software which is not shown in the sheet

- 2. Factor = Insertion loss + Cable loss
- 3. Over limit = Results Limit.



ANNEX A Test Results

A.1 20dB Occupied Bandwidth





No	Ant	Frequency(kHz)	20dB Bandwidth(Hz)
2	Ant2	136.535	564

	n Analyzer - Occupied BW RF 50 Ω AC	1 12	ENSE:PULSE SOUP		01-50-01	PM Mar 14, 2024	
	136.595 kHz	Cente	er Freq: 136.595 Free Run n: 10 dB		Radio St		Frequency
10 dB/div	Ref 10.00 dBm			N	lkr1 136 -8.43	.535 kHz 323 dBm	
-og 0.00 10.0			1				Center Fre 136.595 kH
20.0							
50.0							
70.0							
Center 136.6 #Res BW 20		#	łz	Span 1.5 kHz Sweep FFT		CF Ste 150 H	
Occupie	d Bandwidth 425 Hz	Total Powe x dB x dB Ref P	-20.0	dBm 00 dB dBm at	116.5	540 kHz	Auto Ma Freq Offs 0 H
		Lower Boundary		Uppe	r Boundary		
	Freque		Rel Power	Frequency	Abs Power	Rel Power	
Occupied Bandwid dB Bandwidth	136.326 136.255		-14.3 dBc	136.751 kHz 136.819 kHz	-22.5 dBm -34.4 dBm	-14.1 dBc	
SG				ST/	TUS ! AC co	upled: Accy un	spec'd < 10MHz

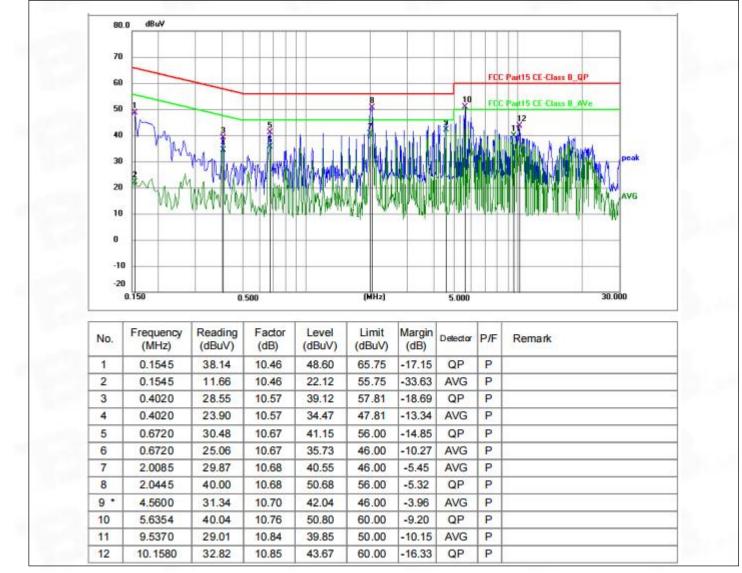


A.2 AC Power Line Conducted Emissions

Note: All the mode have been tested, and only the worst case of mode are in the report

Test Data and Plots

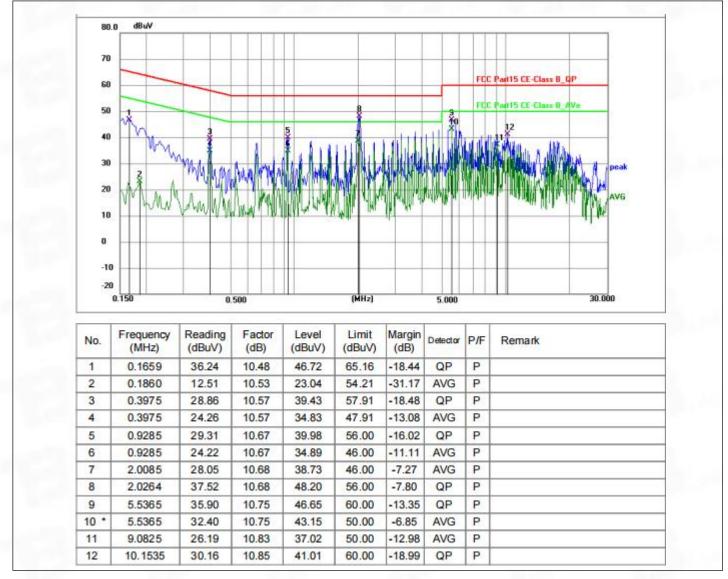
A.2.1 Test at L Phase



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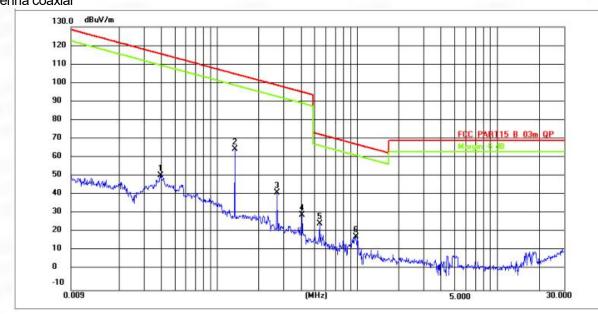
A.2.2 Test at N Phase





A.3 Radiated Spurious Emission

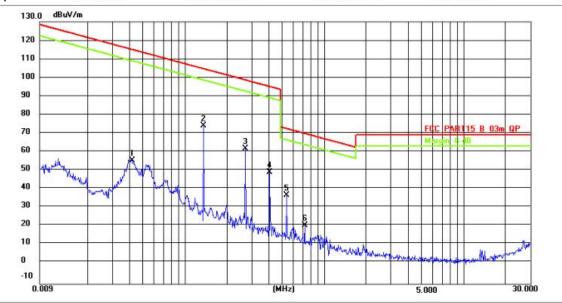
<u>9 kHz ~ 30 MHz</u> Test Antenna coaxial



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	0.0395	81.36	-30.33	51.03	115.66	-64.63	peak	P
2 *	0.1335	95.05	-29.97	65.08	105.09	-40.01	peak	P
3	0.2691	71.80	-29.65	42.15	99.00	-56.85	peak	P
4	0.4040	59.30	-29.36	29.94	95.48	-65.54	peak	P
5	0.5390	54.52	-29.04	25.48	72.97	-47.49	peak	P
6	0.9820	46.54	-28.04	18.50	67.72	-49.22	peak	P



Test Antenna coplanar

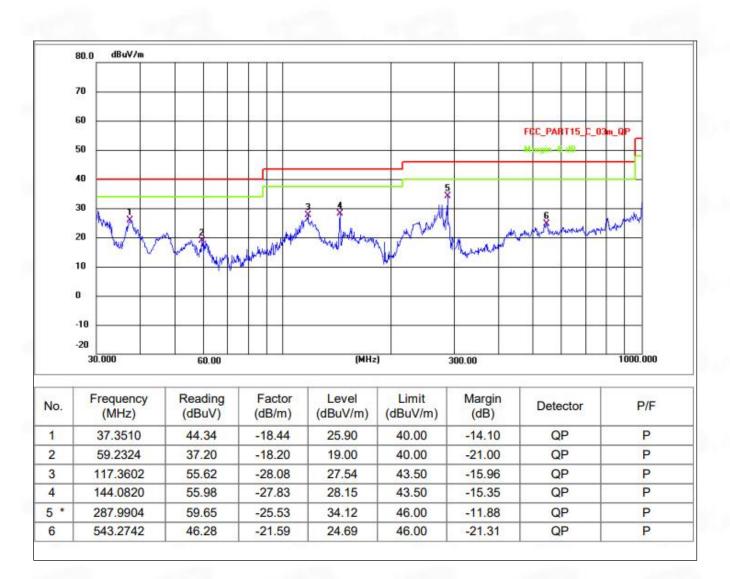


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	0.0415	86.27	-30.32	55.95	115.23	-59.28	peak	P
2 *	0.1355	104.54	-29.95	74.59	104.96	-30.37	peak	P
3	0.2701	91.94	-29.65	62.29	98.97	-36.68	peak	Р
4	0.4057	79.13	-29.34	49.79	95.44	-45.65	peak	P
5	0.5322	66.51	-29.06	37.45	73.08	-35.63	peak	P
6	0.7217	49.95	-28.63	21.32	70.42	-49.10	peak	P

<u>30 MHz ~ 1GHz</u>

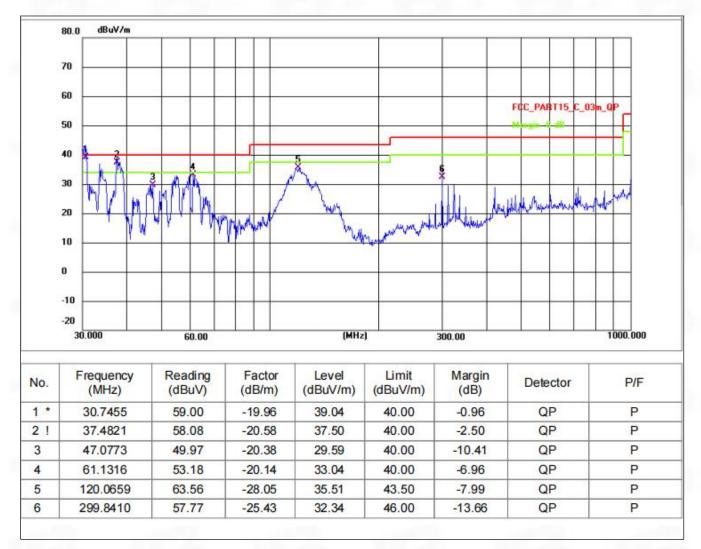
Test Antenna Horizontal (30MHz to 1GHz)



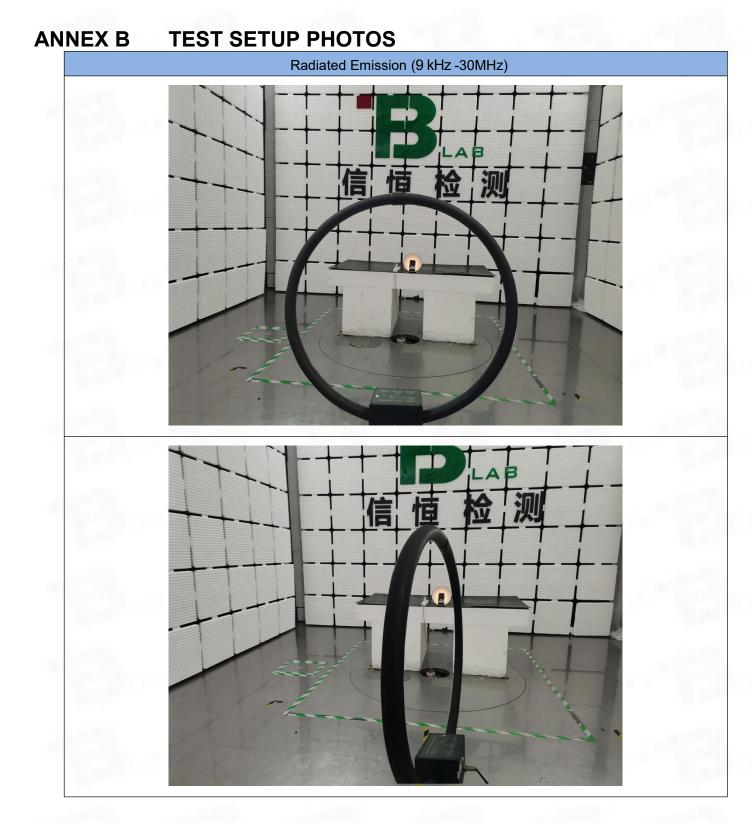




Test Antenna Vertical (30MHz to 1GHz)



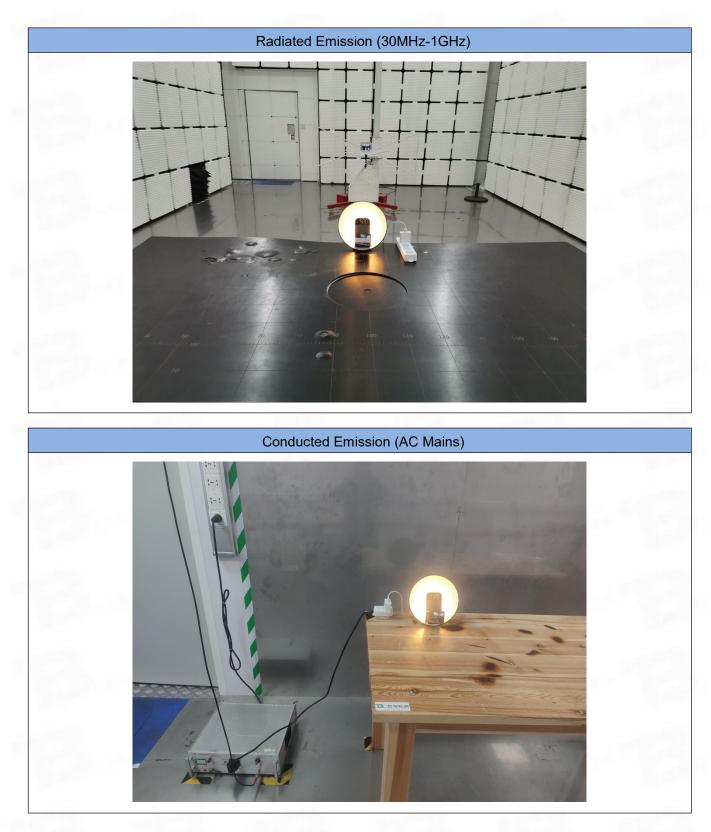




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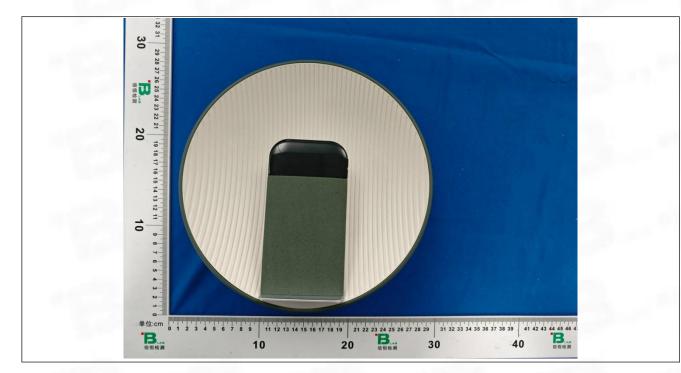
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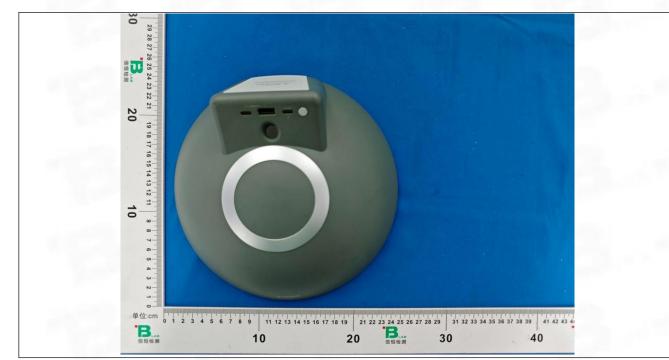






ANNEX C EUT EXTERNAL PHOTOS

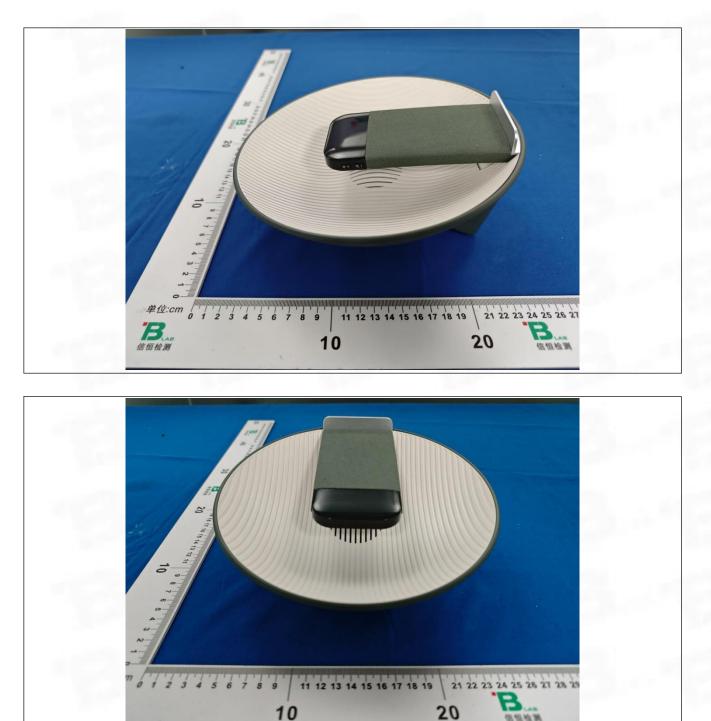




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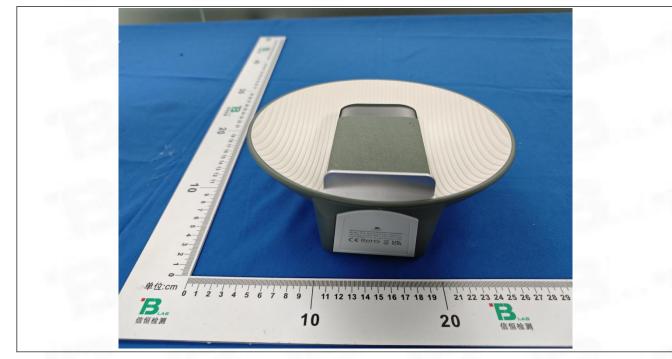




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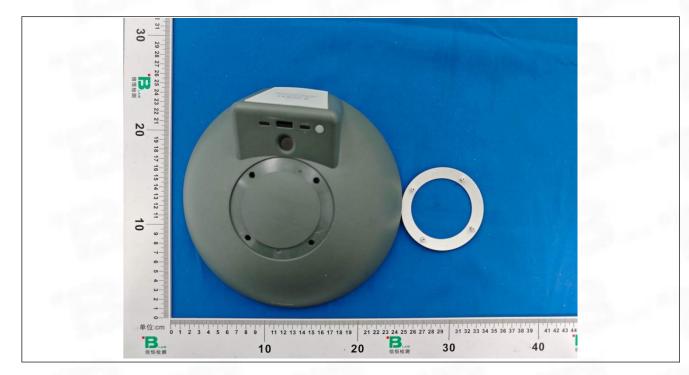


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ANNEX D EUT INTERNAL PHOTOS





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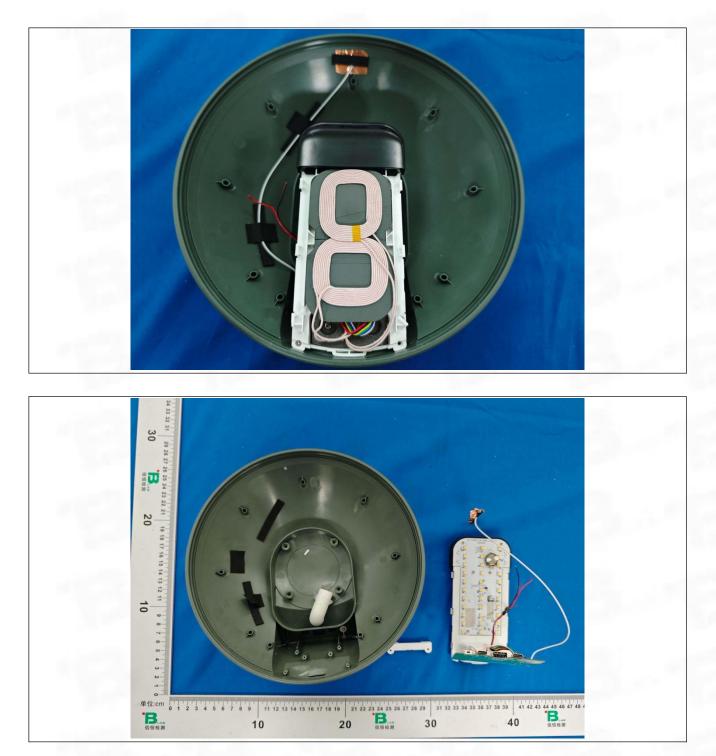
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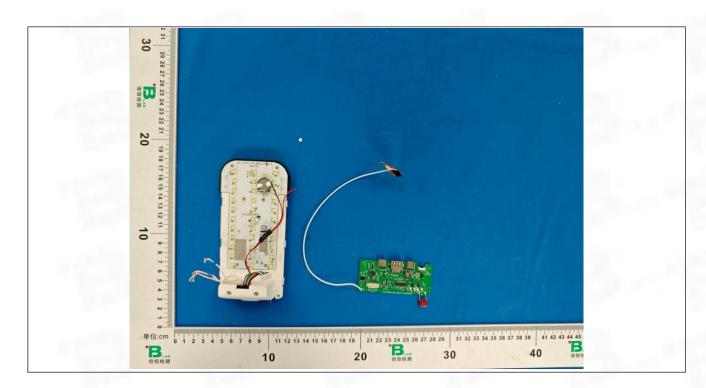


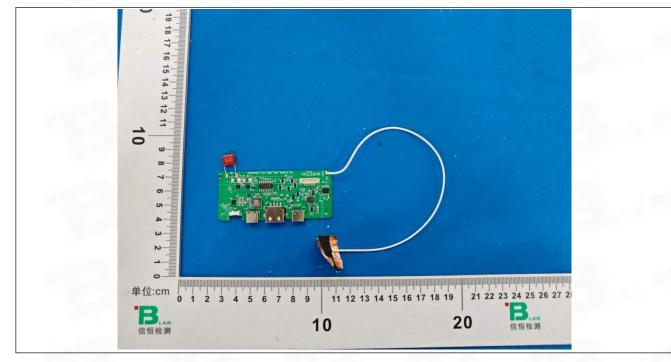


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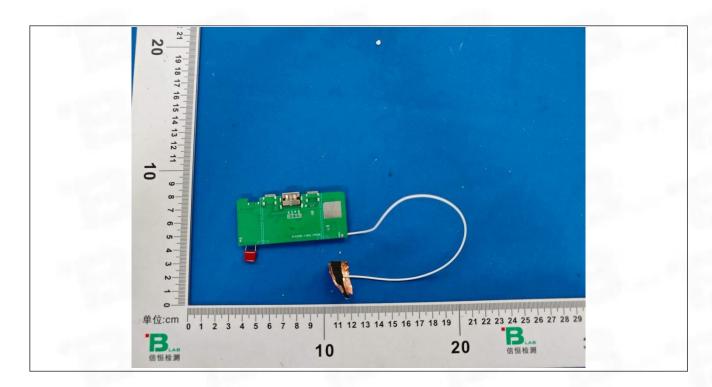


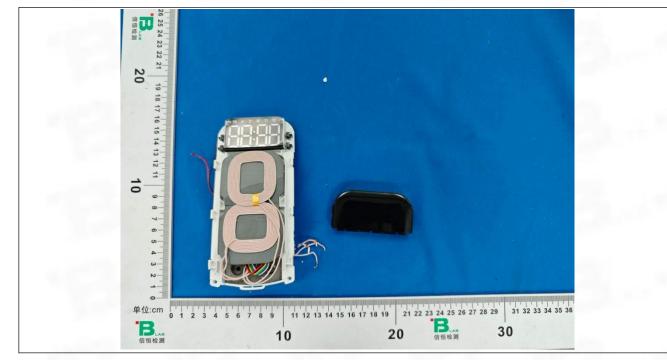


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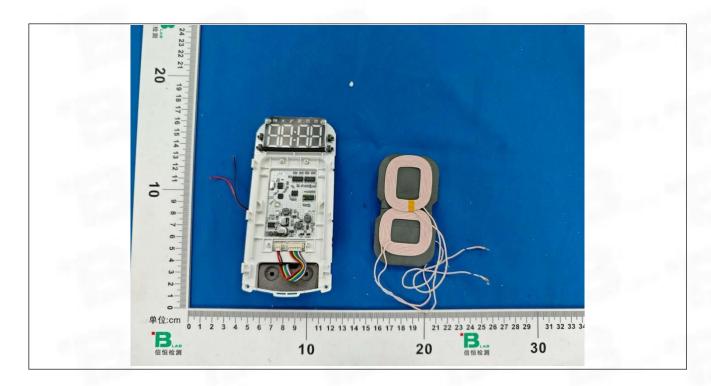


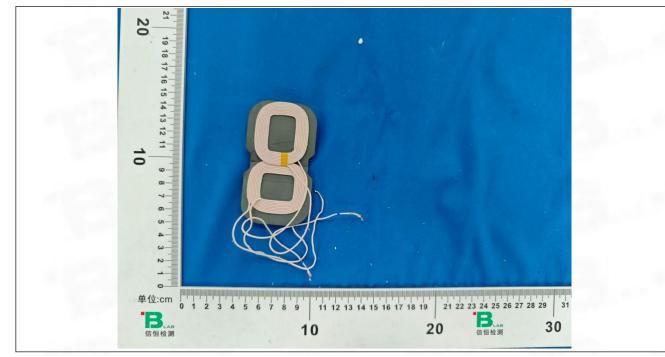




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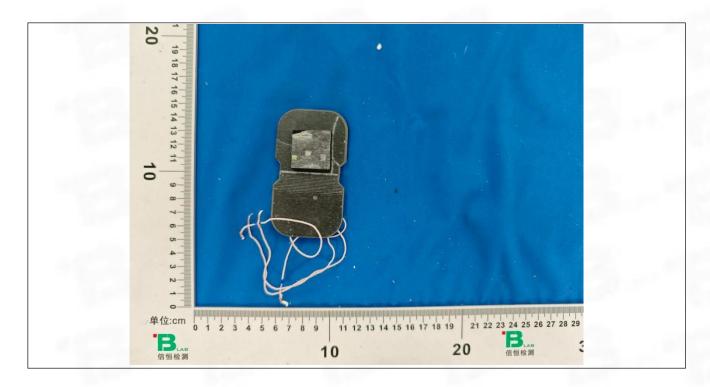


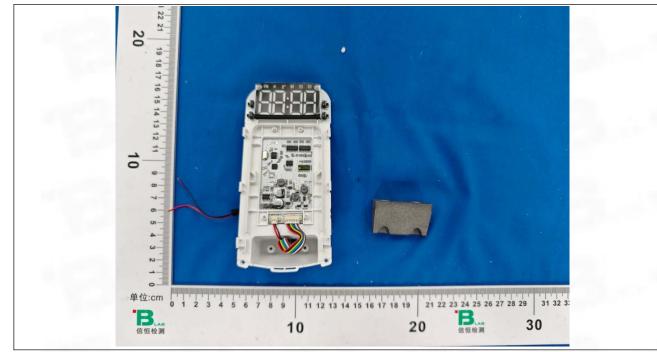


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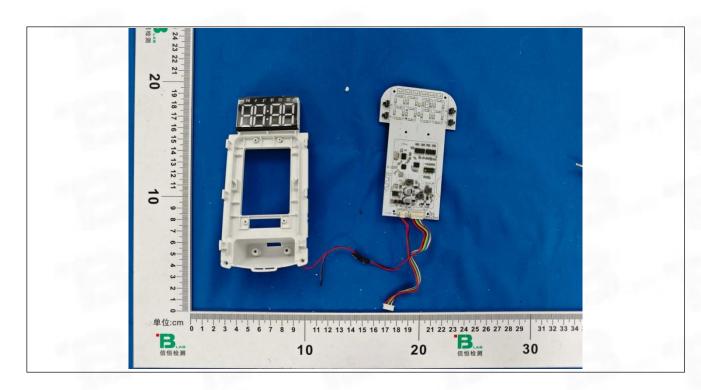


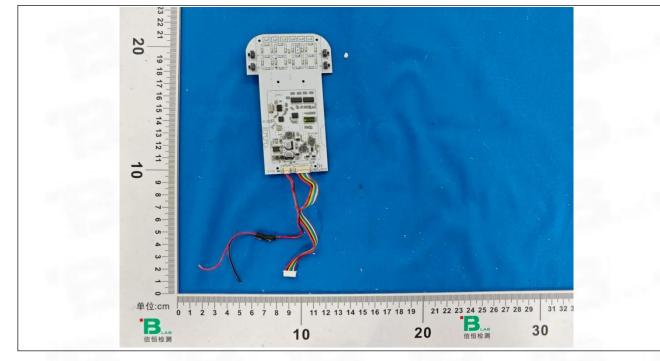




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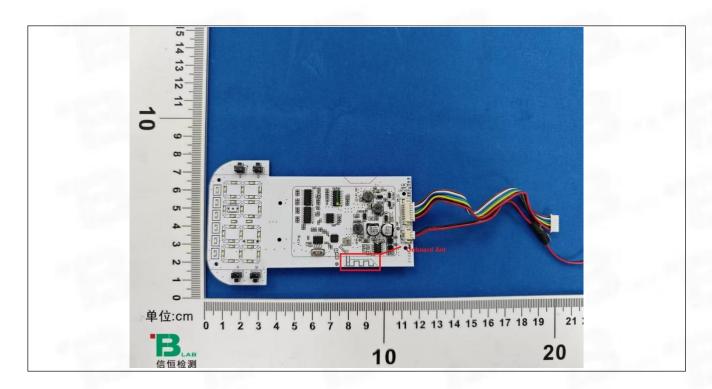


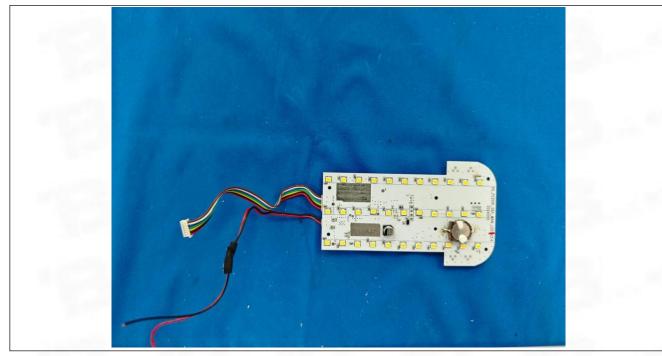


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